

1/6

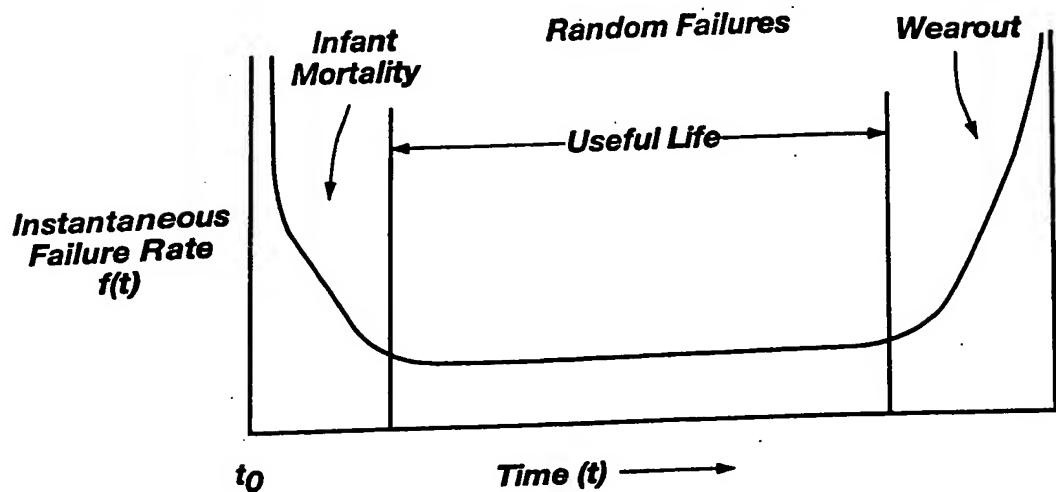


Fig. 1
(PRIOR ART)

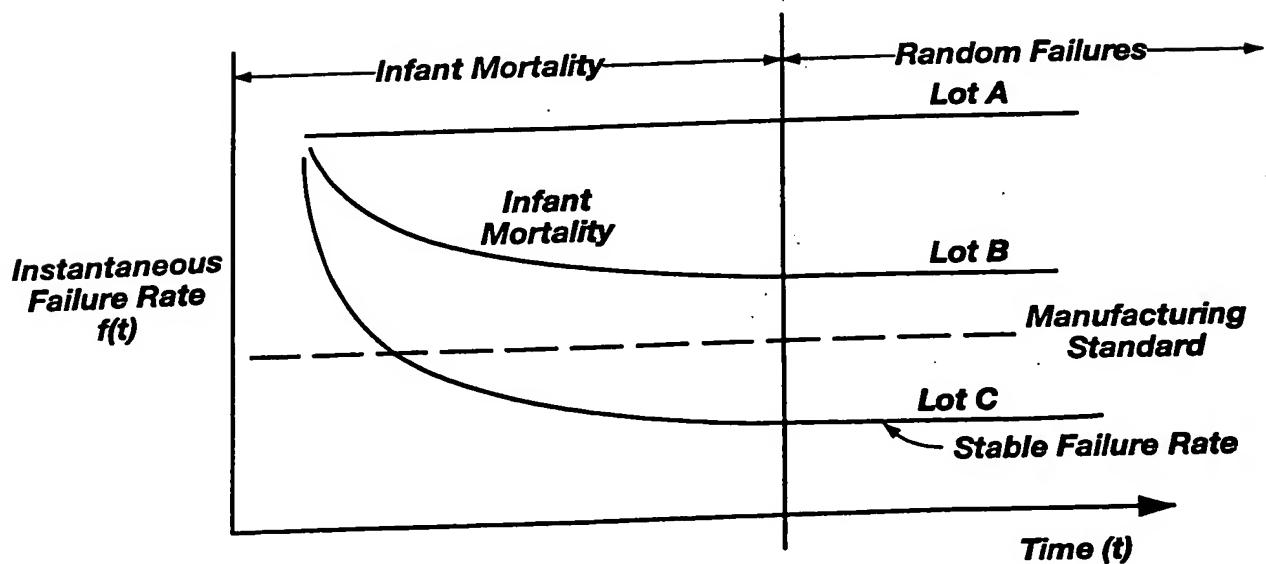


Fig. 2
(PRIOR ART)

TITLE: METHOD AND APPARATUS FOR DETERMINING BURN-IN RELIABILITY FROM WAFER LEVEL BURN-IN

Inventor: Kenneth W. Marr
Docket No.: 2269-5153.1US

2/6

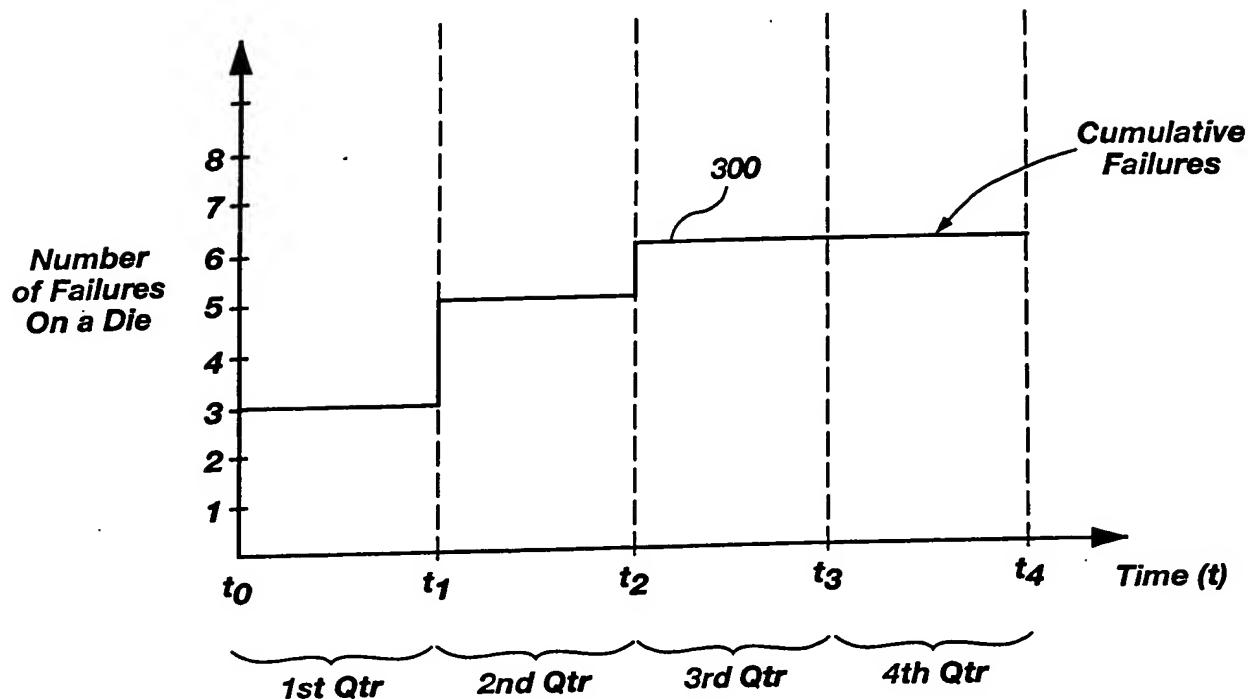


Fig. 3

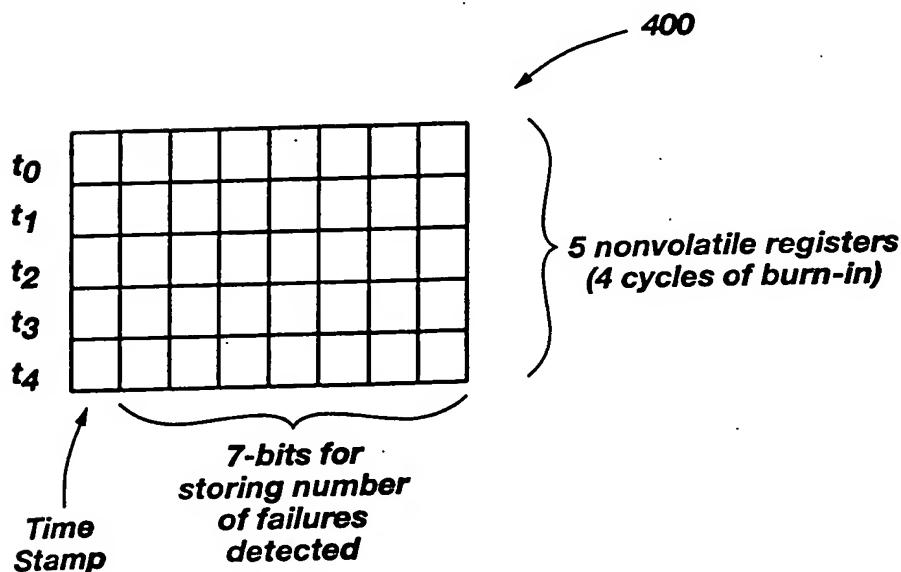


Fig. 4

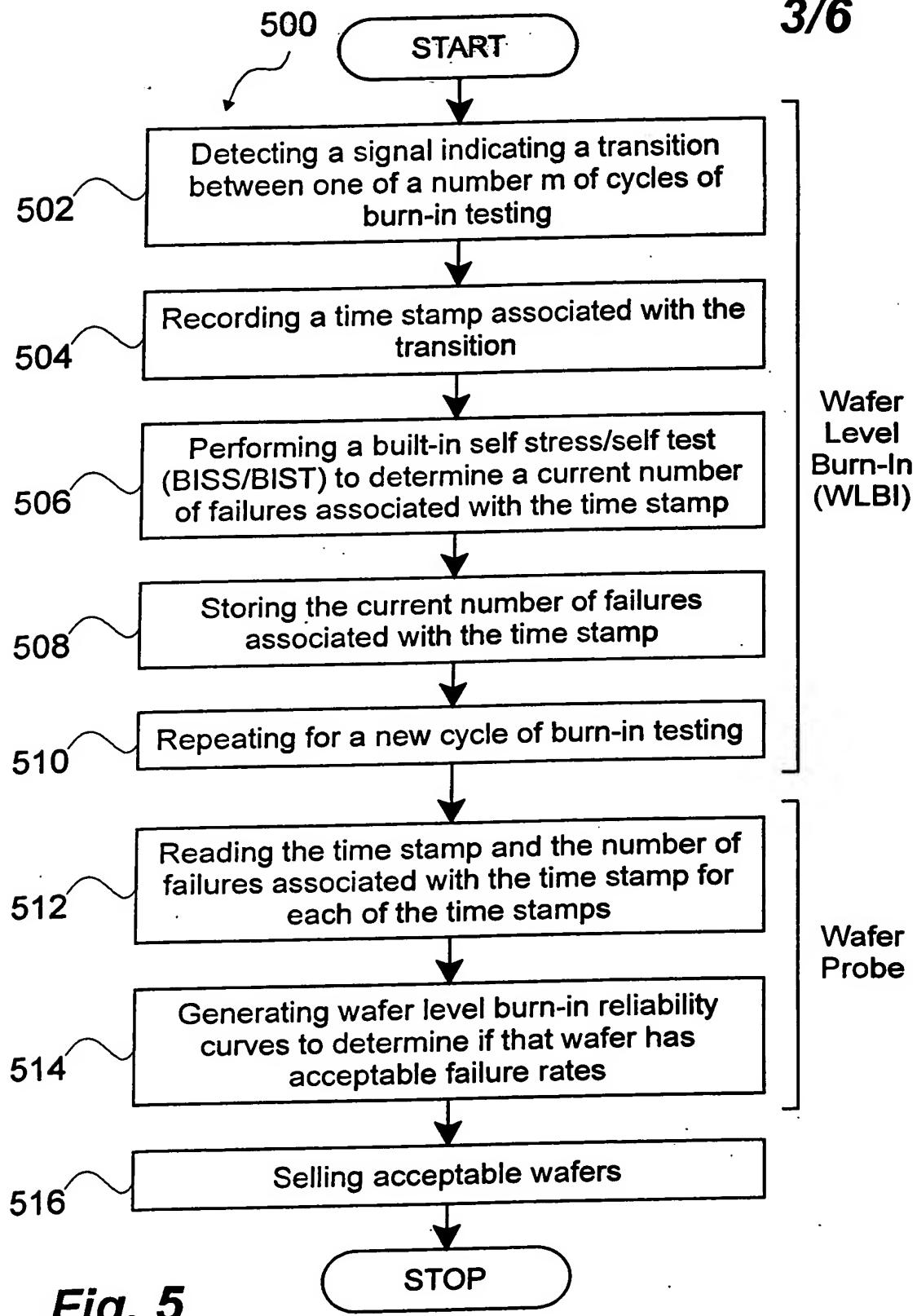


Fig. 5

4/6

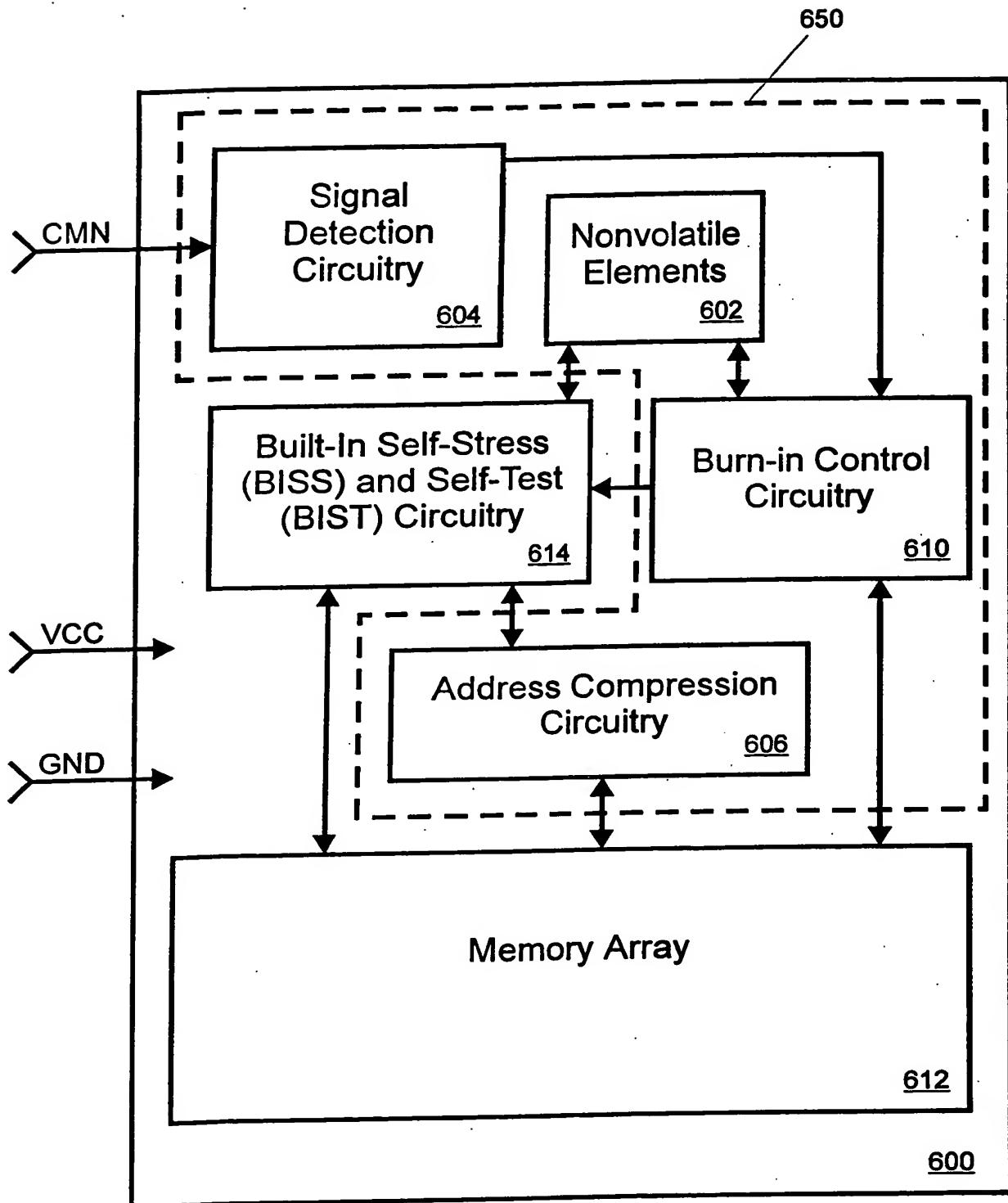


Fig. 6

5/6

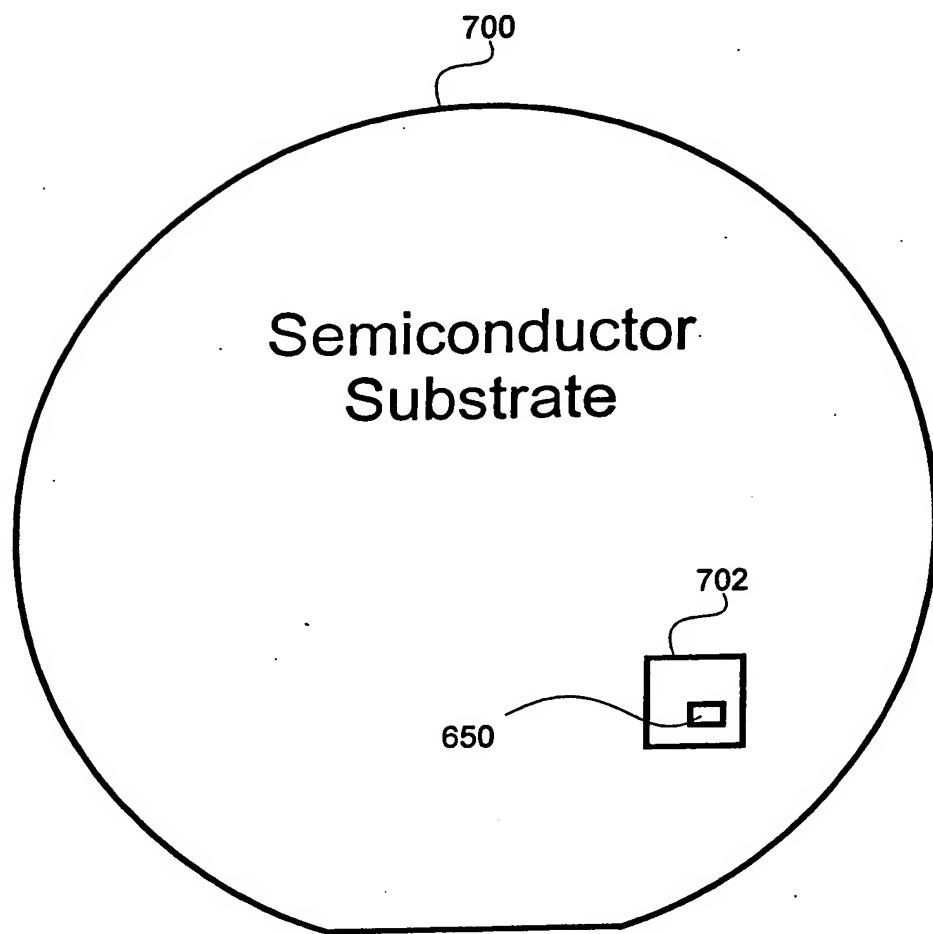


Fig. 7

6/6

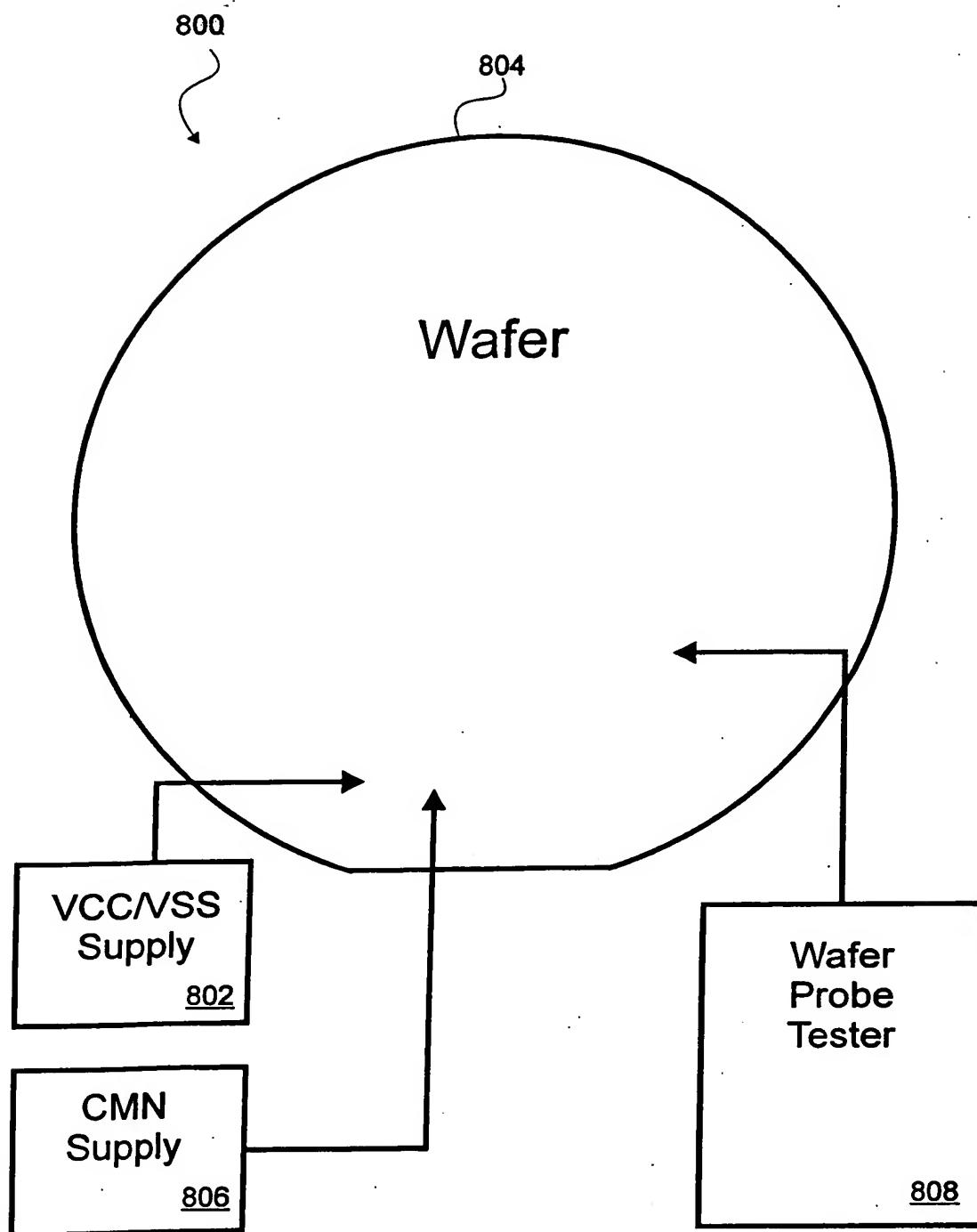


Fig. 8